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Application/Control No.	Applicant(s)/Patent under Reexamination
10/807,714	CHEN ET AL.
Examiner	Art Unit

Tuan Quach

2826

SEARCHED				
Class	Subclass	Date	Examiner	
257	78, 200, 442, 614	7/6/2006	TQ	
	-			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPAT; USPGPUG; EPO; JPO; DERWENT;IBMTDB) - see search history printout	7/6/2006	TQ		